


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/707,806	LAI ET AL.	
	Examiner	Art Unit	
	David E. Martinez	2181	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	52,53	6/21/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent,		6/21/2006	DM

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East see attached	6/21/2006	DM
Inventor Search eDan	6/21/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	6/21/2006	DM
710/52,53,57.ccls. with keywords and text search	6/21/2006	DM